Applying a basic op amp current amplifier to photodiodes presents three severe problems: high nonlinearity, oscillations, and a latch condition. All three result from the presence of load-signal voltage feedback to the photodiode. A simple bootstrapping arrangement can remove them all.

In the basic circuit, Figure 1, two resistors, $R_1$ and $R_2$, control the positive and negative feedback, respectively. Consequently, they also control the current amplifier’s gain. All the signal current, $i_p$, from the photodiode flows through $R_1$ (negligible current flows into the op amp’s input), thereby defining the input-to-output voltage drop of the op amp. Because of the op amp’s very high open-loop gain and the feedback arrangement, the circuit replicates that voltage across $R_2$ to keep the differential voltage between the op amp inputs close to zero. As a result, feedback current $i_O$ flows into the load $Z_L$ through $R_2$. Thus, the current gain $i_O/i_p$ or $A_i$, equals $R_1/R_2$.

Because the photodiode’s responsivity changes as its voltage changes with light input, voltage variation across $Z_L$, which is also across the photodiode, causes nonlinearity. Even worse, the photodiode’s capacitance, $C_D$, rolls off the negative feedback from $R_1$ at high frequencies. Consequently, the positive feedback from $R_2$ can dominate, and oscillations, can result. In fact, $C_D$ inadvertently converts the circuit to a conventional op amp square-wave generator. If large enough to stop oscillations, a dominant roll-off bypass capacitor $C_B$ added across the load would devastate the circuit’s bandwidth.

Moreover, under the condition of input overloads, which can occur during turn-on, a high impedance load could create a latch state in conjunction with the diode. If the load impedance supports a great enough voltage, positive feedback takes continuous control at the amplifier’s noninverting input. At the inverting input, the photodiode clamps the voltage and prevents negative feedback recovery.

Bootstrapping, though, removes each of the problems caused by load voltage on the photodiode (see Figure 2). In the new circuit, the load voltage drives the end of the photodiode that’s grounded in the basic circuit. Also, a feedback-tee circuit option becomes possible. With only the very small op amp differential input error signal across the photodiode, its response is essentially linear. Moreover, the canceled-out positive feedback signal on $C_D$ avoids the square-wave generator action.

Through its effect on feedback, bootstrapping preserves bandwidth in two ways. The negative-feedback network riding on top of the positive-feedback signal always ensures a net negative feedback. The circuit requires little, if any, load bypassing. As a result, this arrangement reduces the bandwidth-limiting bypassing effect of the load and its capacitance comparable to that of traditional current-to-voltage conversion circuits. Also, because positive feedback can no longer dominate, the circuit eliminates input clamping by the photodiode and the latch state.

The bootstrapping circuit also benefits from the use of a feedback-tee network. In the bootstrapping circuit, the tee, like the photodiode, also rides atop the load to similarly avoid the positive-feedback effects. Tee networks offer a degree of frequency-response control. In the tee, capacitor $C_1$ blocks the low-frequency shunting effects of $R_3$ to produce a high-pass response without an amplified offset voltage. (Request PDS-653.)

![FIGURE 1. Basic Photodiode Circuit.](image1)

![FIGURE 2. Bootstrapped Photodiode Circuit.](image2)
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